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Application No. <u>10/081439</u>	Prepared by <u>BQU</u>	Tracking Number <u>593/401</u>	
Examiner-GAU <u>WILLIE-2814</u>	Date <u>5/11/04</u>	Week Date <u>4/5/04</u>	
	No. of queries <u>1</u>	<u>IFW (Ru4)</u>	

JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	(p.) PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION

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- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
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- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

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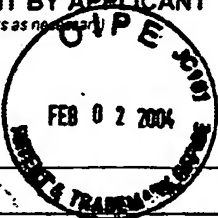
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<i>Complete if Known</i>	
Applicant Number	10/081439
Filing Date	February 20, 2002
First Named Inventor	Ahn, Kie
Group Art Unit	2818
Examiner Name	Unknown

Sheet 1 of 2

Attorney Docket No: 1303.046US1

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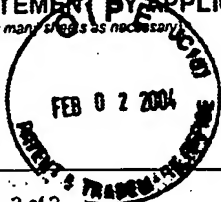
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Group Art Unit	2818
Examiner Nam	Unknown
Attorney Docket No: 1303.046US1	

Sheet 2 of 2

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Application Number	10/081439
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First Named Inventor	Ahn, Kie
Group Art Unit	2818
Examiner Name	Unknown

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OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

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